





RESPONSE UNDER 37 CFR 1.116 EXPEDITED PROCEDURE EXAMINING GROUP 2851

00862.022246

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
	: Examiner: H. Nguyen
Kazunori IWAMOTO et al.)
	: Group Art Unit: 2851
Application No.: 09/866,600)
	: Confirmation No.: 4961
Filed: May 30, 2001)
	•
For: STAGE APPARATUS WHICH SUPPORTS INTERFEROMETER,) August 6, 2004
STAGE POSITION MEASUREMENT METHOD, PROJECTION	, ,
EXPOSURE APPARATUS, PROJECTION EXPOSURE))
APPARATUS MAINTENANCE METHOD SEMICONDUCTOR	•
DEVICE MANUFACTURING METHOD, AND)
SEMICONDUCTOR MANUFACTURING FACTORY	<i>)</i>
SEMICONDUCTOR MANUFACTURING FACTOR I	•

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Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.

X No additional fee is required.

The fee has been calculated as shown below:

		· r	CLAIMS AS AME	NDED			
	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRES	SENT EXTRA	RATE	ADDITIONAL FEE
TOTAL CLAIMS	30	MINUS	31	=	0	x \$9 \$18	\$0.00
INDEP. CLAIMS	6	MINUS	7	=	0	x \$43 \$86	\$0.00
Fee for Mu	altiple Dependent claims	\$145/\$290					
			TOTAL ADDITION FOR THIS AMEND				\$0.00

	°Verified Statement claiming small entity status is enclosed, if not filed previously.				
	A check in the amount of \$ is enclosed including the additional claims fees.				
	Charge \$ to Deposit Account No. 06-1205. A duplicate of this sheet is enclosed.				
X	Any prior general authorization to charge an issue fee under 37 CFR 1.18 to Deposit Account No. 06-1205 is hereby revoked. The Commissioner is hereby authorized to charge any additional fees under 37 CFR 1.16 and 1.17 which may be required during the entire pendency of this application, or to credit any overpayment, to Deposit Account No. 06-1205. A duplicate of this paper is enclosed.				
	A check in the amount of \$ to cover the fee for a two month extension is enclosed.				
	A check in the amount of \$ to cover the Information Disclosure Statement fee is enclosed.				
X	Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should be directed to our address given below.				
	Respectfully submitted,				
	Attorney for Applicants Steven E. Warner Registration No. 33,326				

FITZPATRICK, CELLA, HARPER & SCINTO 30 Rockefeller Plaza
New York, New York 10112-3801
Facsimile: (212) 218-2200

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For: STAGE APPARATUS WHICH SUPPORTS)	August 6, 2004
INTERFEROMETER, STAGE POSITION	:	
MEASUREMENT METHOD, PROJECTION)	
EXPOSURE APPARATUS, PROJECTION	:	
EXPOSURE APPARATUS MAINTENANCE)	
METHOD, SEMICONDUCTOR DEVICE	:	
MANUFACTURING METHOD, AND)	
SEMICONDUCTOR MANUFACTURING FACTORY	:	

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Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL REJECTION

Sir:

In response to the final Official Action dated May 7, 2004, please amend the above-identified application as follows, pursuant to 37 C.F.R. § 1.116: